

Impact of random and determinist acoustic noise on vibrations at high frequencies of a free-fixed beam Benoit BOLZON LAViSta

Laboratories in Annecy working on Vibration and Stabilisation

Catherine ADLOFF	Andrea JEREMIE	Jacques LOTTIN
Benoît BOLZON	Yannis KARYOTAKIS	Laurent BRUNETTI
Franck CADOUX	Claude GIRARD	Fabien FORMOSA
Yan BASTIAN	Nicolas GEFFROY	

European LC Workshop; January 8-9 2007; Daresbury Laboratory

Introduction

✓ Linear collider: 2 FD stabilisation at the subnanometer scale

- Ground motion negligible above 300Hz
- Acoustic noise above?

✓ Goal of this presentation:

Studies on the acoustic noise impact on free-fixed beam (ILC configuration) vibrations above 300Hz

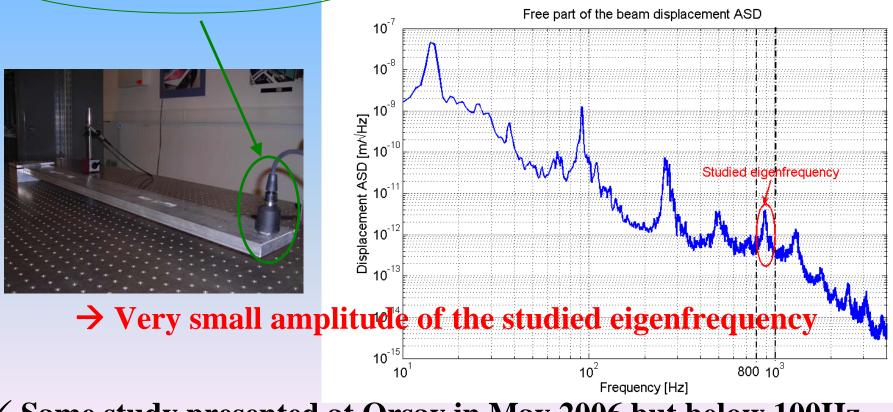
Conclusion on the necessity to stabilise the 2 FD above 300Hz

Introduction

✓ Studies on a 1 metre free-fixed beam with a full rectangular section

Acoustic noise impact on a high eigenfrequency: [800-1000]Hz

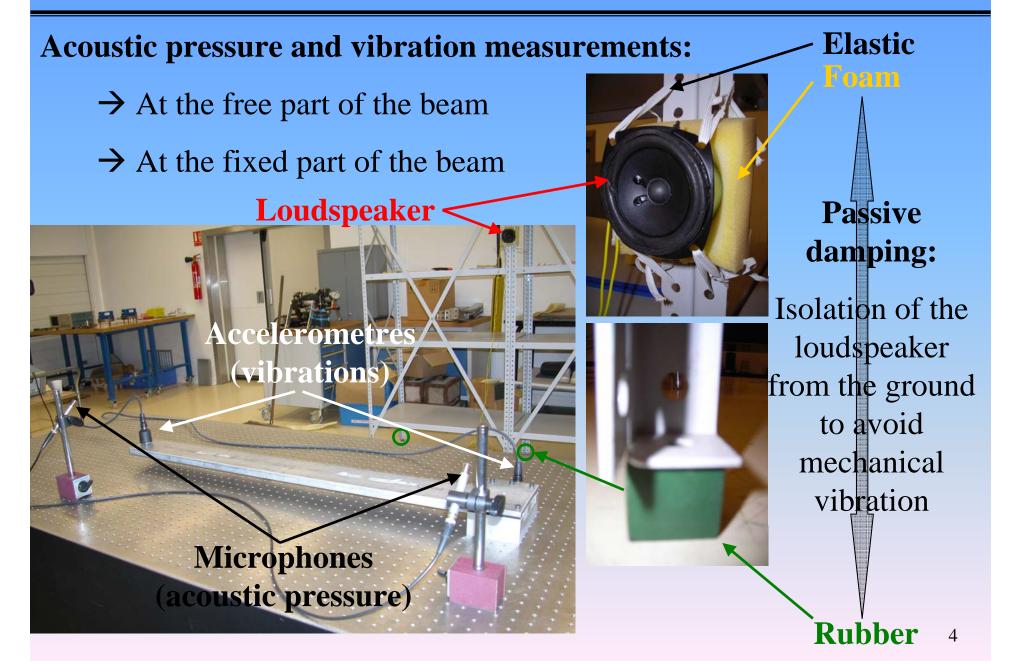
Vibration measurements in the LAVISTA working room



✓ Same study presented at Orsay in May 2006 but below 100Hz

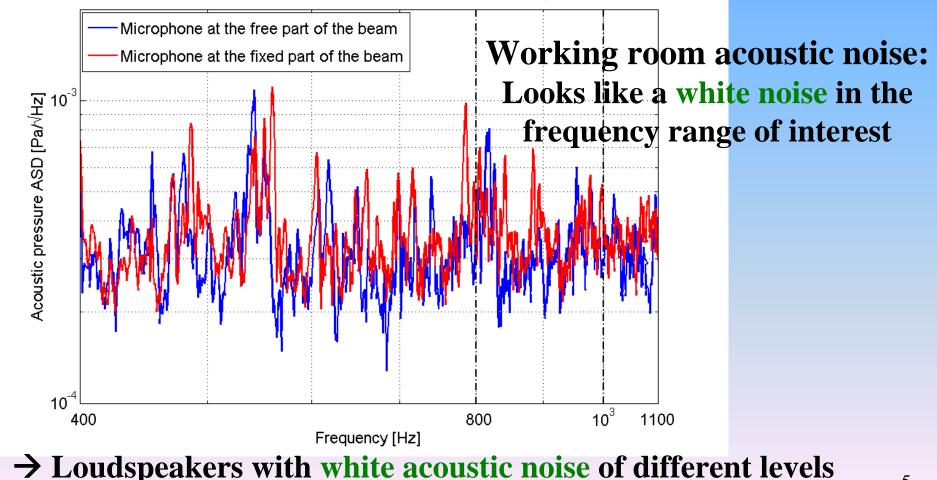
3

Experimental set-up



Experimental set-up

✓ Random acoustic noise impact study on the [800-1000]Hz eigenfrequency: Working room acoustic noise simulation



Acoustic pressure ASD measured in the LAVISTA working room

Experimental set-up

✓ Determinist acoustic noise impact study on the [800-1000Hz] eigenfrequency: Pump noise simulation

Loudspeakers with 881Hz sine of different levels

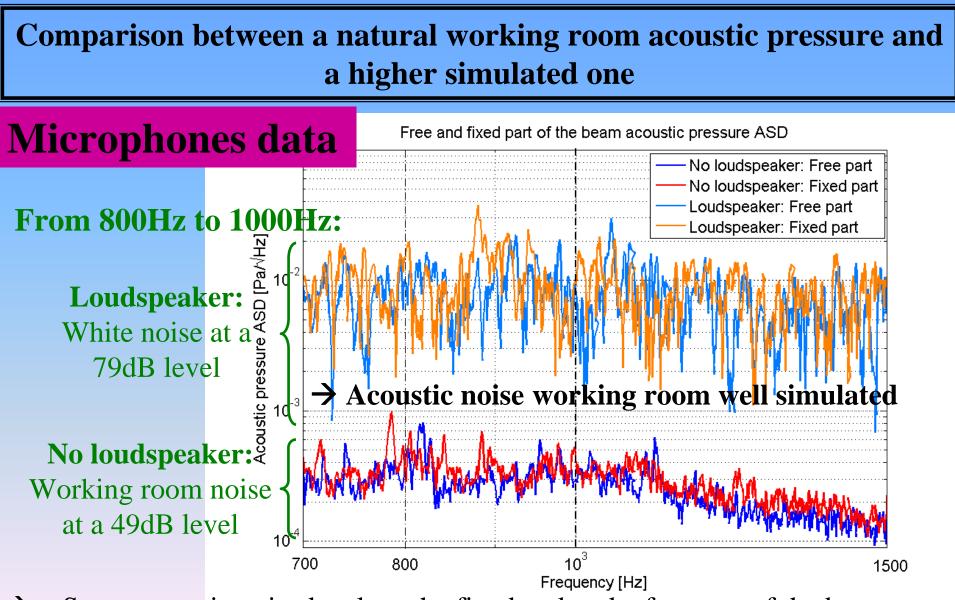
✓ For each level of acoustic noise:

Acquisition of microphones/accelerometres data

Sensors Data sheet

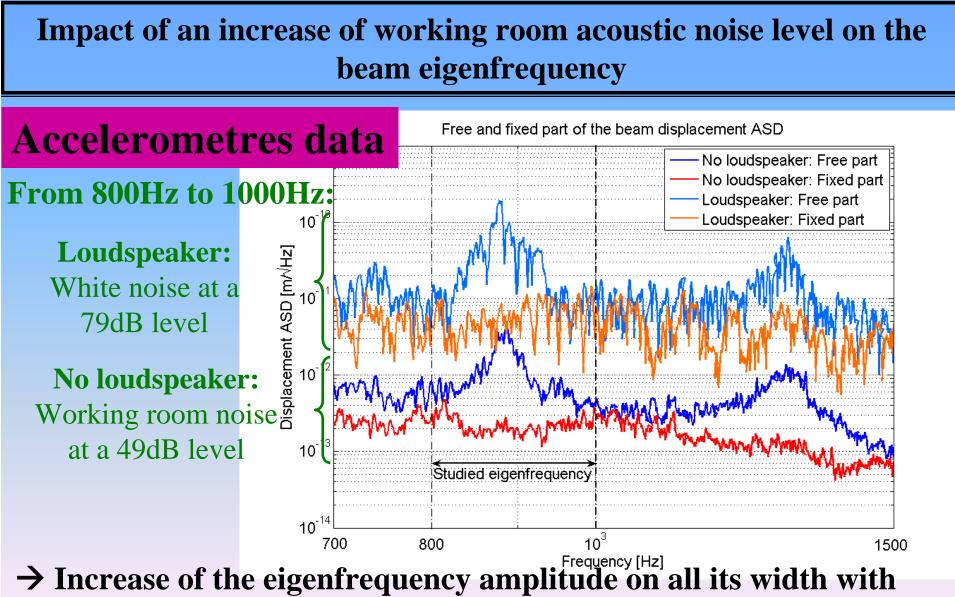
Sensors	Accelerometres 393B12	Microphone 4189
Sensitivity	10V/g	50mV/Pa
Frequency range	0.1 - 4 kHz	6 – 20 kHz
Quantity	2	2

White acoustic noise



 \rightarrow ~ Same acoustic noise levels at the fixed and at the free part of the beam γ

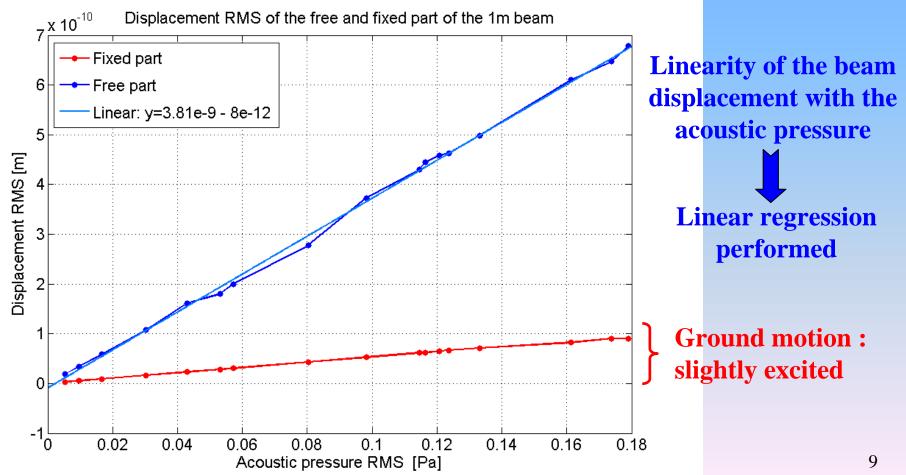
White acoustic noise



white acoustic noise

White acoustic noise Integrated displacement RMS of the free and fixed part of the beam versus Integrated acoustic pressure RMS

→ Integrated RMS in [800-1000Hz]



White acoustic noise **Integrated displacement RMS of the free and fixed part of** the beam versus Integrated acoustic pressure RMS \rightarrow Integrated RMS in [800-1000Hz] 7 × 10⁻¹⁰ Displacement RMS of the free and fixed part of the 1m beam 0.68nm **Small increase of Range of Sound Pressure Levels** Sound Pressure, p Sound Pressure Level, L [Pa] acoustic pressure 6 140 [dB] 100 10 Displaquent RMS [m] 1 79dB 0.1 2dB 0.01 Non negligible beam **49dB** 0.001 displacement in the 20 0.000 1 0.000 01 frequency range Brülei & Kiær 🛋 Fixed part [800-1000Hz] BA 7665-11, 12, 8805057 Free part 0.09nm1 **Ground motion :** No loudspeaker 0.04nm slightly excited 0.02nm 3.3pm0 9dB50 55 65 70 72dB 75 60 79dB80 Acoustic pressure RMS [dB]

Comparison between a natural working room acoustic pressure and a pump acoustic pressure simulated **Microphones data** Free and fixed part of the beam acoustic pressure ASD Free and fixed part of the beam acoustic pressure ASD No loudspeaker: Free part No loudspeaker: Free par **From 800Hz to 1000Hz:** No loudspeaker: Fixed part Loudspeaker: Free part Loudspeaker: Fixed part Loudspeaker: Fixed part Loudspeaker: c noise ASD [m/√Hz] 0.____01 10 zoom Sine noise at a Acoustic 10 79dB level 10⁻² 880.5 881 881.5 Acoustic noise pump well simulated No loudspeaker: Working room noisĕ ĕ 10⁻³ at a 49dB level '00 750 881 900 800 850 950 1000 Frequency [Hz]

 \rightarrow ~ Same acoustic noise levels between the fixed and the free part of the beam

Impact of a pump acoustic noise on the beam eigenfrequency

Accelerometres data Free and fixed part of the beam displacement ASD 10⁻⁹ No loudspeaker: Free part No loudspeaker: Fixed part **From 800Hz to 1000Hz:** Loudspeaker: Free part • Displacement ASD [m//Hz] Loudspeaker: Fixed part Loudspeaker: Eigenfrequency Sine noise at a 79dB level No loudspeaker: **10⁻¹²** Working room noise at a 49dB level 10^{-1} 800 881 700

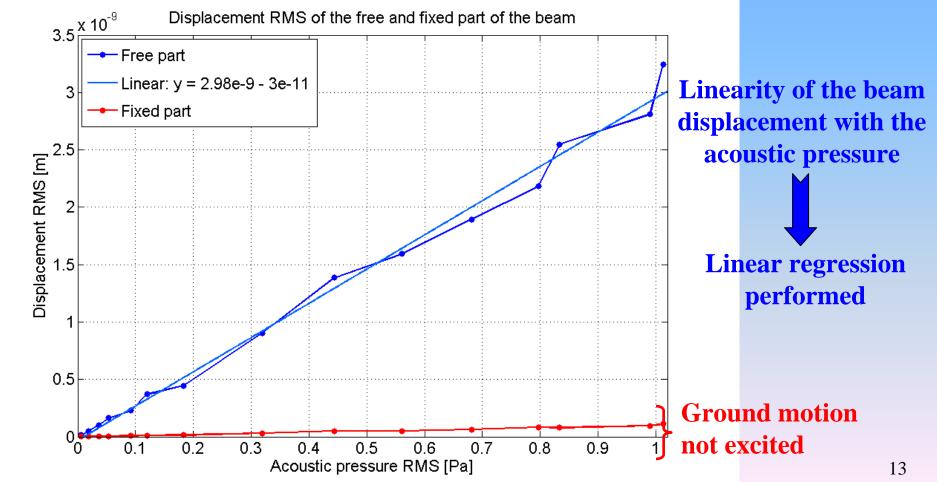
 \rightarrow Huge increase of the eigenfrequency amplitude at the sine frequency

→ Non increase of the eigenfrequency amplitude outside the sine frequency

 10^{3}

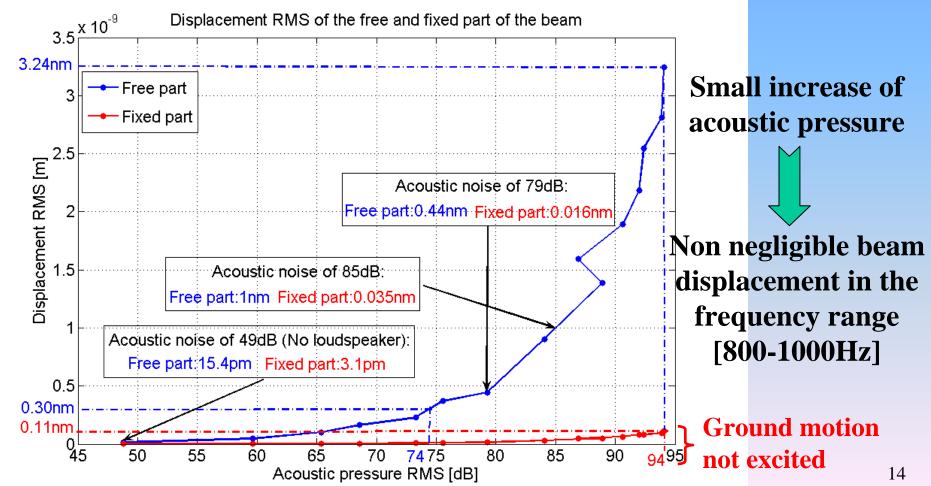
Integrated displacement RMS of the free and fixed part of the beam versus Integrated acoustic pressure RMS

→ Integrated RMS in [800-1000Hz]



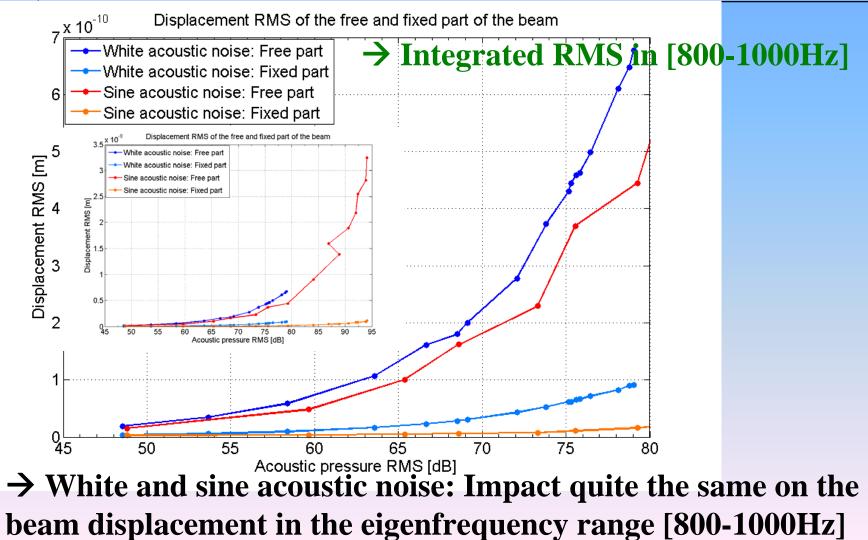
Integrated displacement RMS of the free and fixed part of the beam versus Integrated acoustic pressure RMS

→ Integrated RMS in [800-1000Hz]



Summary: Sine and white acoustic noise

Integrated displacement RMS of the free and fixed part of the beam versus Integrated acoustic pressure RMS



15

Conclusion

✓ Small increase of random/determinist acoustic pressure in the frequency range [800Hz-1000Hz]

 \rightarrow Non negligible displacement of the free-fixed beam because of the resonance induced at the given eigenfrequency

✓ Linear collider: environment with high acoustic noise

 \rightarrow Necessary to stabilise also above 300Hz to at least 1000Hz!!!

 \rightarrow Good acoustic pressure coherence may help for relative stabilisation (Need to go on with this coherence study)

 \rightarrow Alternative: fixed-fixed beam configuration

✓ Predictive model : only ground motion excitation

 \rightarrow Should include acoustic noise

Vibration active rejection in the nanometre scale:

First results

Presentation of the instrumentation

Data sheet

✓ NI PCI-6052 Multifunction DAQ

PCI-6052E	Quantity	Resolution	Rate	Conversion	Range	Noise
Analog	8 Differential/	16bits	Up to 333kS/s	Successive	±0.05 to 10V	60uV from
Input	16 Single-ended			approximation		DC to 1MHz
Analog	2 Single-ended	16 bits	333kS/s	Successive	±10V	
output				approximation		

Fast card

Low noise card

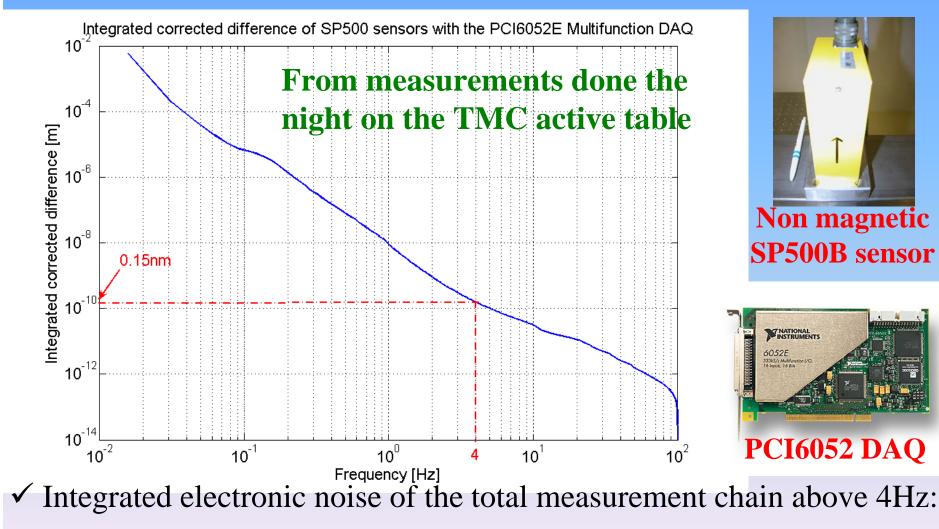
Compatible Matlab/Simulink (Softwares used for the algorithm)

✓ Sensors used to do vibration active control

Sensors	SP500B	ENDEVCO86	
Sensitivity	2000V/m/s	10V/g	
Frequency range	0.0167 – 75Hz	0.01 - 100 Hz	
Integrated electronic noise above 4Hz	0.085nm	0.6nm	
Quantity	2	2	
	Non magnetic	18	

Presentation of the instrumentation

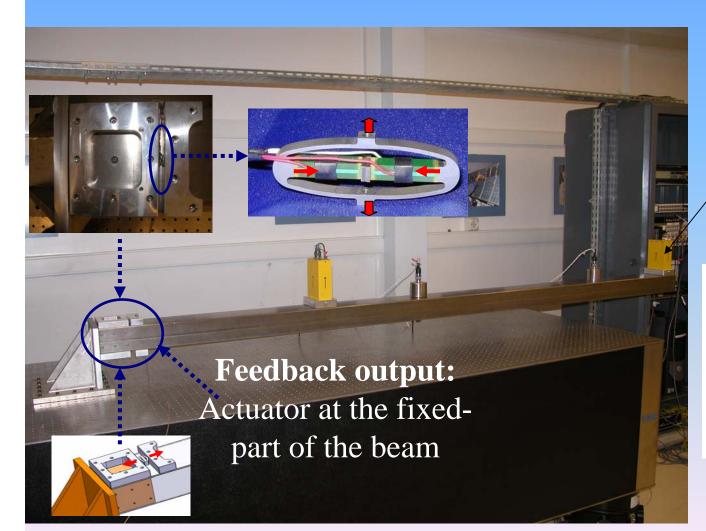
Measurement chain electronic noise



 \geq 0.15nm : enough to do active control at the nanometre scale₁₉

First results of stabilisation in the nanometre scale

Experimental set-up



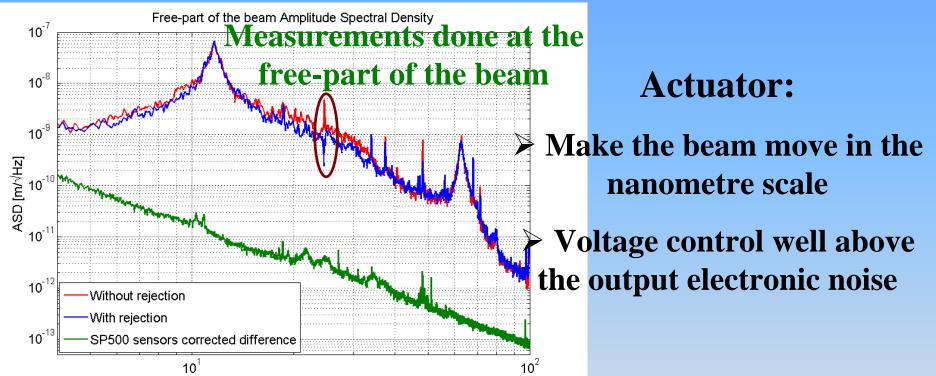
Feedback input: Sensor at the freepart of the beam



PCI6052 DAQ: Sensor acquisition and actuator control

First results of stabilisation in the nanometre scale

Active rejection of one unknown disturbance frequency



✓ Rejection ok with the initial algorithm (state space) for frequencies which correspond to unknown source disturbances

For eigenfrequencies, necessity to control a larger bandwidth

 \rightarrow Test of a new algorithm (internal model command), which need also just a punctual knowledge of the system ²¹

Conclusion

✓ Instrumentation OK to work in the nanometre scale:

Measurement chain: Integrated electronic noise of 0.15nm above 4Hz

Actuator: Make the beam move in the nanometre scale for a voltage control well above the output electronic noise

✓ Feedback loop:

Today: Work well for narrow picks

> Test of a new algorithm to control eigenfrequencies

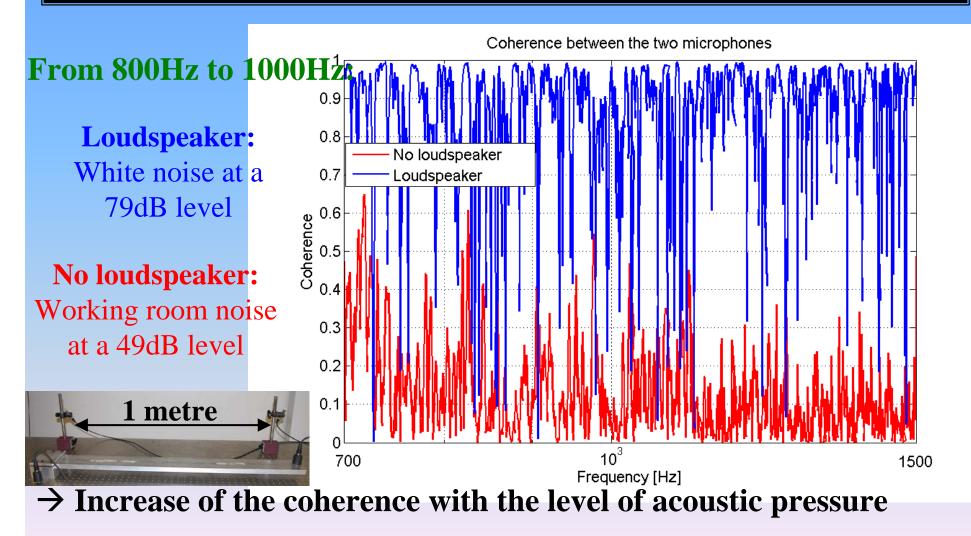
✓ Future prospects:

> Improvement of the algorithm for multiple inputs/outputs

> New algorithm based on position control to work on a very large bandwidth: important if necessary to stabilise above 300^J_Hz

White acoustic noise

Acoustic pressure coherence for two levels of white acoustic noise



 \rightarrow 79dB level: Quite good coherence between the 2 microphones ²³